



SUBJECT AREAS:  
STRUCTURE OF SOLIDS  
AND LIQUIDS

SCANNING PROBE  
MICROSCOPY

MATERIALS FOR DEVICES

SURFACES, INTERFACES AND  
THIN FILMS

SCIENTIFIC REPORTS:

3 : 2399

DOI: 10.1038/srep02399  
(2013)

Published:  
9 August 2013

Updated:  
20 November 2013

## **ERRATUM:** Atomic Structures of Silicene Layers Grown on Ag(111): Scanning Tunneling Microscopy and Noncontact Atomic Force Microscopy Observations

Andrea Resta, Thomas Leoni, Clemens Barth, Alain Ranguis, Conrad Becker, Thomas Bruhn, Patrick Vogt & Guy Le Lay

This Article contains a typographical error in the Methods section.

“The room temperature STM experiments were done with an Omicron 1 STM whereas the low temperature experiments were carried out at  $\sim 77$  K in an Omicron low temperature STM/AFM microscope hosted in an ultra-high vacuum chamber with a base pressure in the temperature.”

should read

“The room temperature STM experiments were done with an Omicron 1 STM whereas the low temperature experiments were carried out at  $\sim 77$  K in an Omicron low temperature STM/AFM microscope hosted in an ultra-high vacuum chamber with a base pressure in the  $10^{-11}$  mbar range. The sample and tips were cooled down to liquid nitrogen temperature.”